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(54) **METHOD AND SYSTEM FOR USE OF A FIELD PROGRAMMABLE FUNCTION WITHIN A CHIP TO ENABLE CONFIGURABLE I/O SIGNAL TIMING CHARACTERISTICS**

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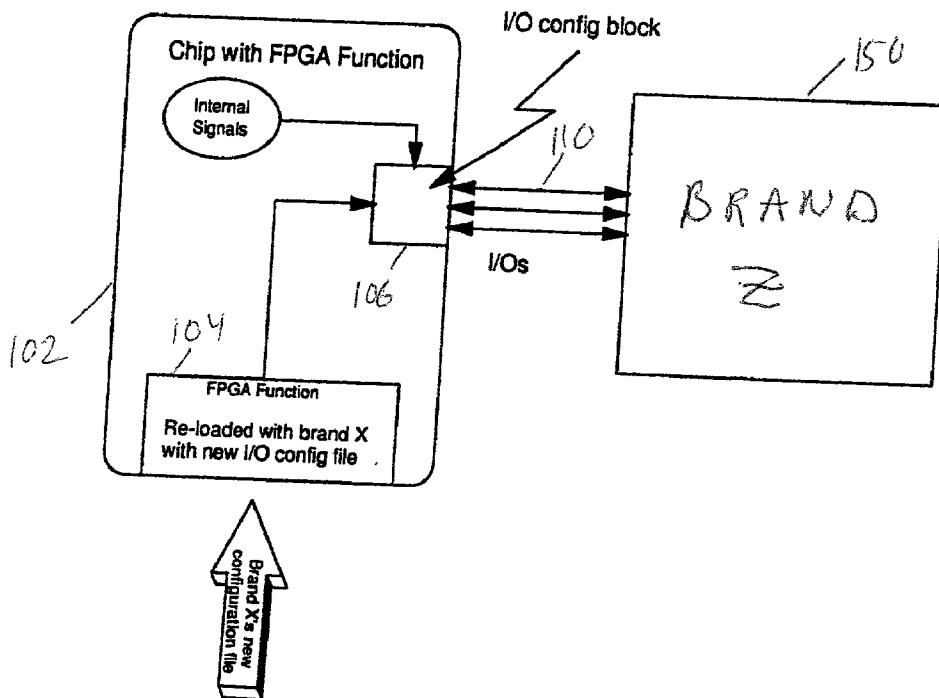
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(57) **ABSTRACT**

An application specific integrated circuit (ASIC) is disclosed. The ASIC includes a standard cell, the standard cell including a plurality of logic functions. The ASIC also includes an input/output (I/O) configuration function coupled to at least a portion of the logic functions. The ASIC further includes a field programmable gate array (FPGA) function coupled to the I/O configuration function. The FPGA function controls the I/O configuration function based upon a configuration file. A system in accordance with the present invention reduces the cost and time associated with the timing analysis activities during development. An FPGA function within the ASIC is utilized to control the I/O characteristics such as delay, termination and/or slew rate for the I/O pin mapping. Different I/O configurations will be provided by the FPGA function depending on the environment the ASIC is used in. By providing an ASIC that is adaptable to different timing criteria through FPGA programming, the timing analysis performed by the user of the ASIC will be substantially reduced, resulting in a reduction of the development cycle.



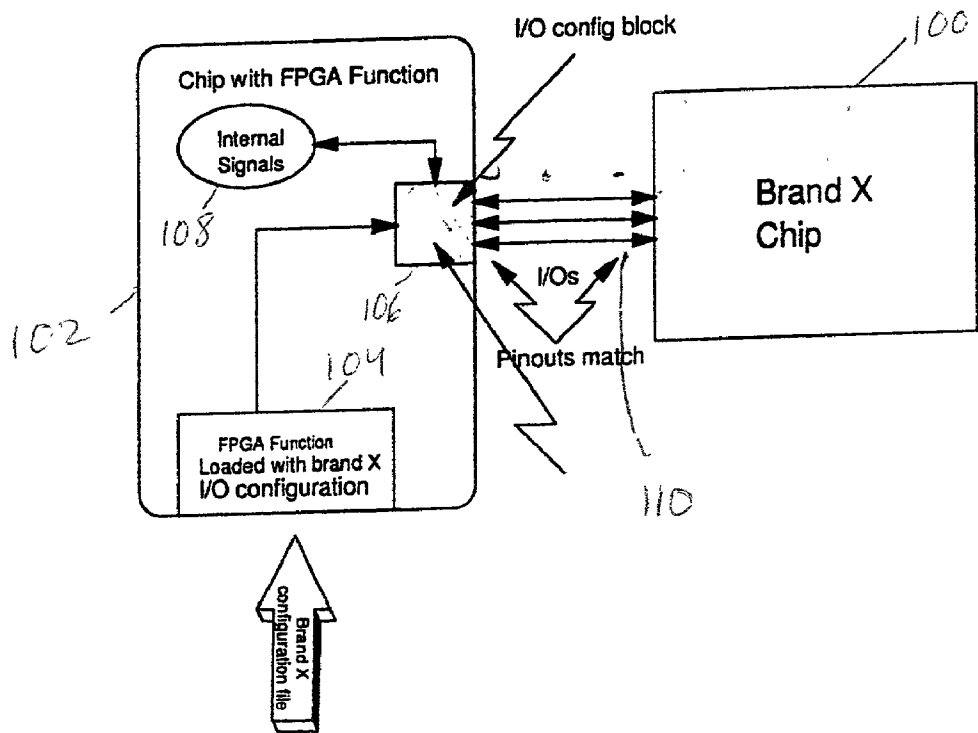


Fig. 1

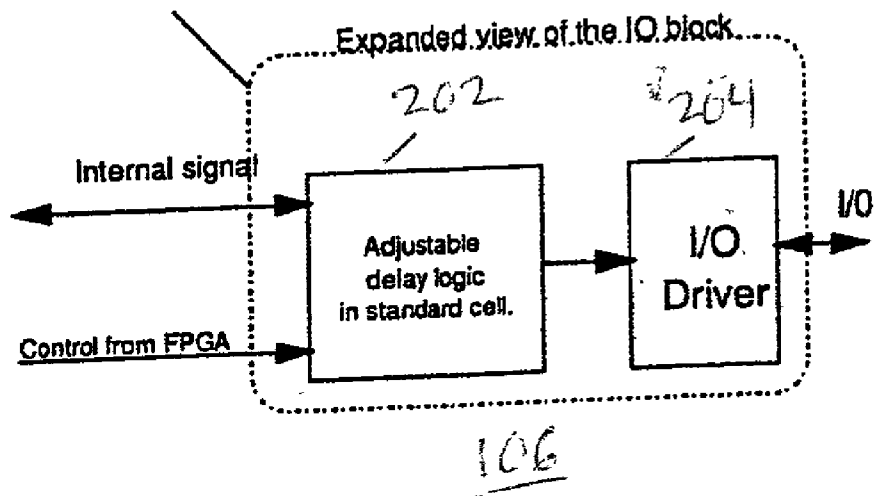


Fig. 1A

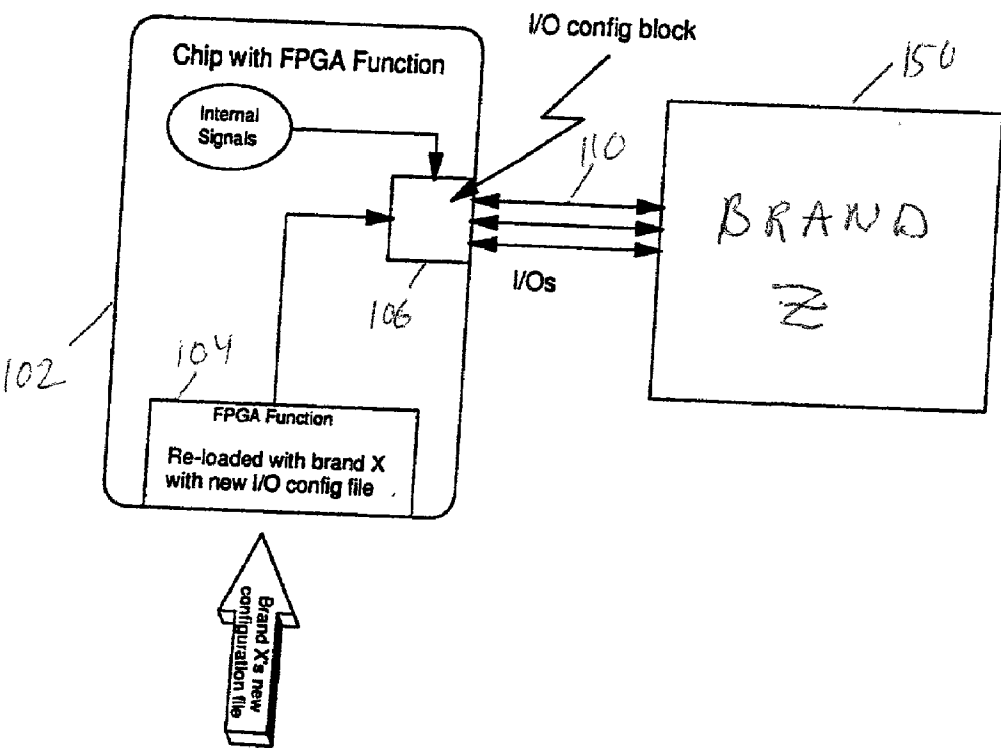


Fig. 2

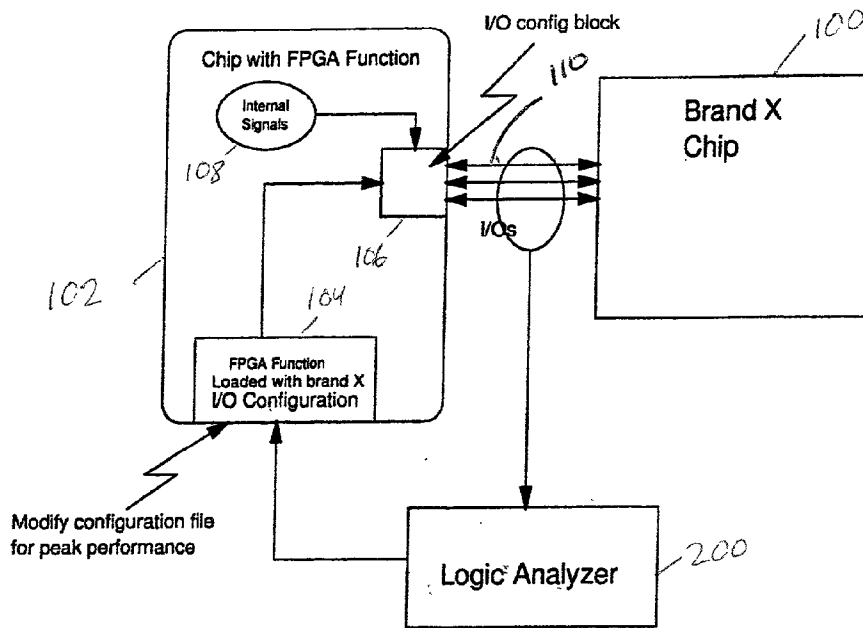


Fig. 3

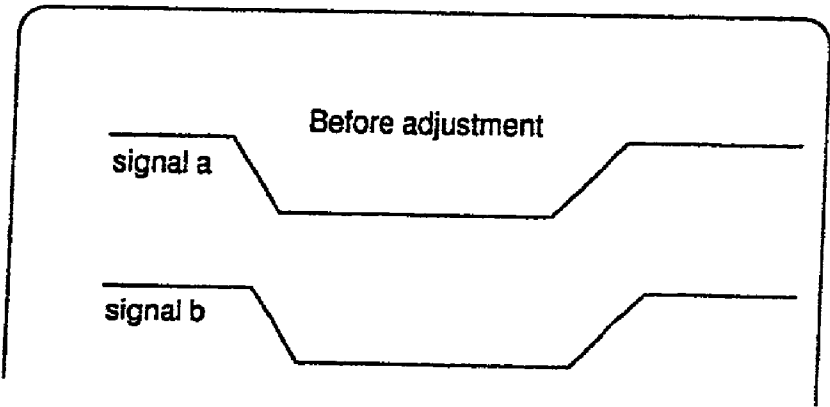


Fig. 3A

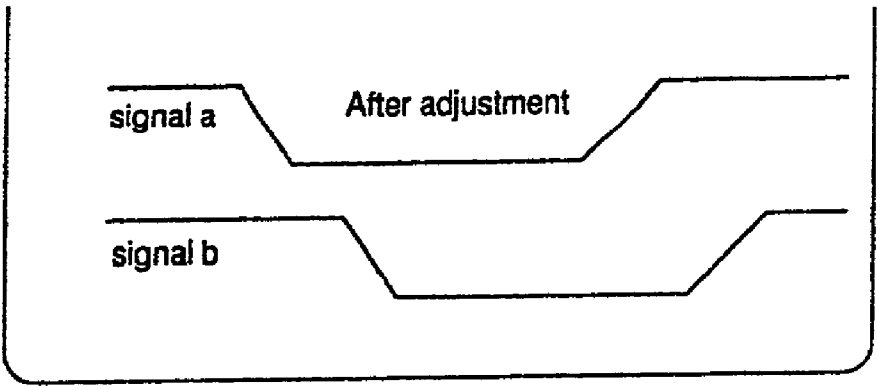


Fig. 3B

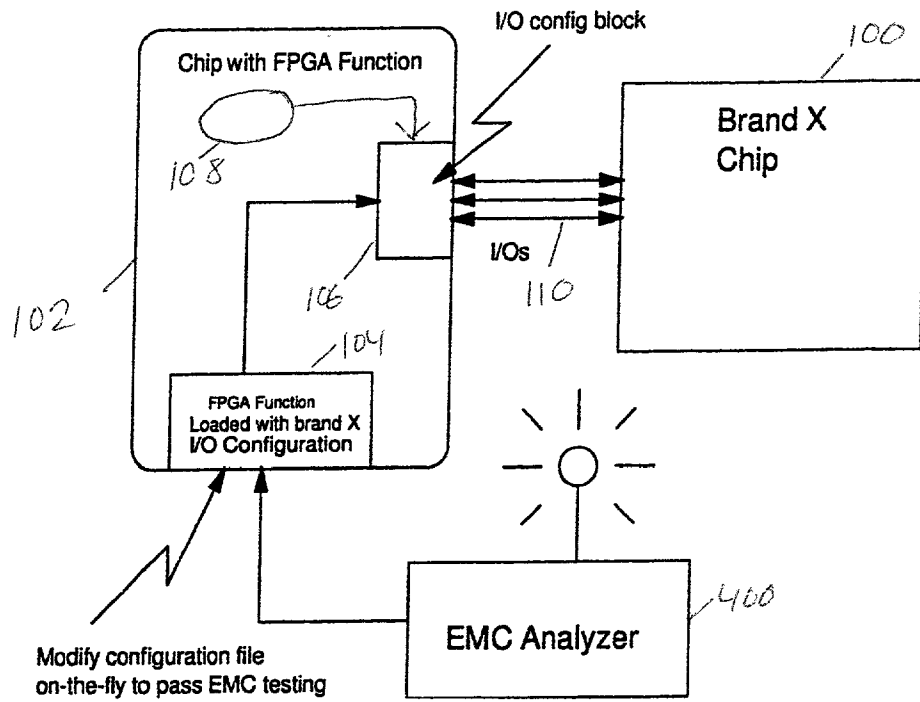


Fig. 4

METHOD AND SYSTEM FOR USE OF A FIELD PROGRAMMABLE FUNCTION WITHIN A CHIP TO ENABLE CONFIGURABLE I/O SIGNAL TIMING CHARACTERISTICS

CROSS-RELATED APPLICATIONS

[0001] The present application is related to the following listed seven applications: Ser. No. _____ (RPS920010125US1) entitled "Field Programmable Network Processor and Method for Customizing a Network Processor;" Ser. No. _____ (RPS920010126US1), entitled "Method and System for Use of an Embedded Field Programmable Gate Array Interconnect for Flexible I/O Connectivity;" Ser. No. _____ (RPS920010127US1), entitled "Method and System for Use of a Field Programmable Gate Array (FPGA) Function Within an Application Specific Integrated Circuit (ASIC) to Enable Creation of a Debugger Client Within the ASIC;" Ser. No. _____ (RPS 920010128US1), entitled "Method and System for Use of a Field Programmable Function Within an Application Specific Integrated Circuit (ASIC) To Access Internal Signals for External Observation and Control;" Ser. No. _____ (RPS920010129US1), entitled "Method and System for Use of a Field Programmable Interconnect Within an ASIC for Configuring the ASIC;" Ser. No. _____ (RPS920010131US1), entitled "Method and System for Use of a Field Programmable Function Within a Standard Cell Chip for Repair of Logic Circuits;" and Ser. No. _____ (RPS920010132US1), entitled "Method and System for Use of a Field Programmable Gate Array (FPGA) Cell for Controlling Access to On-Chip Functions of a System on a Chip (SOC) Integrated Circuit;" assigned to the assignee of the present application, and filed on the same date.

FIELD OF THE INVENTION

[0002] The present invention relates generally to application specific integrated circuits (ASICs) and specifically to configuring I/O signal timing characteristics of such a circuit.

BACKGROUND OF THE INVENTION

[0003] The high clock speeds of today's application specific integrated circuits (ASICs) demand that critical timing to external devices must be met. During the development cycle, great effort is spent to complete timing analysis and design a printed circuit board that will meet all of the timing specifications. If the same ASIC is used in a different design, the timing analysis effort needs to be reanalyzed. The timing constraints make the printed board layout more difficult, resulting in a longer development cycle.

[0004] Time to market is very critical in the product life cycle. Often the design engineer is challenged by a complex design and short development schedules. It would be very attractive to be able to design with high speed ASICs without the intense timing analysis. In some cases, there are no resources (engineers, equipment, tools, knowledge, and time) to complete successful timing analysis. Currently, timing and EMC issues are solved by a combination of delay lines, PCB layout, selection of proper vendor for external devices, ferrite beads and enclosure requirements. These techniques are time consuming and expensive. Sometimes there is not enough resources and/or time to complete a successful design.

[0005] Accordingly, what is needed is a system and method to overcome the above-identified problems. The present invention addresses such a need.

SUMMARY OF THE INVENTION

[0006] An application specific integrated circuit (ASIC) is disclosed. The ASIC includes a standard cell, the standard cell including a plurality of logic functions. The ASIC also includes an input/output (I/O) configuration function coupled to at least a portion of the logic functions. The ASIC further includes a field programmable gate array (FPGA) function coupled to the I/O configuration function. The FPGA function controls the I/O configuration function based upon a configuration file.

[0007] A system in accordance with the present invention reduces the cost and time associated with the timing analysis activities during development. An FPGA function within the ASIC is utilized to control the I/O characteristics such as delay, pin mapping, termination and/or slew rate for the I/O. Different I/O configurations will be provided by the FPGA function depending on the environment the ASIC is used in. By providing an ASIC that is adaptable to different timing criteria through FPGA programming, the timing analysis performed by the user of the ASIC will be substantially reduced, resulting in a reduction of the development cycle.

BRIEF DESCRIPTION OF THE DRAWINGS

[0008] FIG. 1 is a block diagram illustrating a particular chip coupled to an ASIC.

[0009] FIG. 1A is an expanded block diagram of the I/O configuration block.

[0010] FIG. 2 illustrates the ASIC being coupled to a chip with different timing than the chip in FIG. 1.

[0011] FIG. 3 illustrates the use of a logic analyzer to collect data and modify the configuration file of the FPGA function.

[0012] FIG. 3A illustrates two signals (signal a and signal b) before an adjustment.

[0013] FIG. 3B illustrates signal b delayed to adjust timing.

[0014] FIG. 4 illustrates the use of an electromagnetic compatibility analyzer that can be used to obtain information to be used to modify the I/O configuration to ensure that there is EMC compliance.

DETAILED DESCRIPTION

[0015] The present invention relates generally to application specific integrated circuits (ASICs) and specifically to configuring I/O signal timing characteristics of such a circuit. The following description is presented to enable one of ordinary skill in the art to make and use the invention and is provided in the context of a patent application and its requirements. Various modifications to the preferred embodiment and the generic principles and features described herein will be readily apparent to those skilled in the art. Thus, the present invention is not intended to be limited to the embodiment shown but is to be accorded the widest scope consistent with the principles and features described herein.

[0016] FIG. 1 is a block diagram illustrating a particular chip 100 coupled to an ASIC 102. The ASIC 102 includes an FPGA function 104. The FPGA function 104 is coupled to an I/O configuration block 106. The I/O configuration block 106 is also coupled to internal signals 108. As is seen, the I/O signals 110 are coupled from the chip 100 to an I/O configuration block 106 of the ASIC 102. The FPGA function 104 is loaded with a configuration that matches the configuration of the chip 100 to ensure proper timing between I/O channel 110 and/or pinouts. Accordingly, a configuration file is loaded into the FPGA function 104 that then communicates that configuration file to the I/O configuration block 106. In so doing, the I/Os pinouts match to minimize timing problems. To further describe this matching function refer now to FIG. 1A.

[0017] FIG. 1A is an expanded block diagram of the I/O configuration block 106. The I/O configuration block 104 includes an adjustable delay logic 202 and an I/O driver 204 coupled to the adjustable delay logic 202. The adjustable delay logic 202 is in a standard cell array. The configuration file which is loaded into the FPGA function 104 (FIG. 1) allows the FPGA to control the adjustable delay logic 202 to provide the appropriate timing to the I/O driver 204.

[0018] Having a ASIC 102 that can change its I/O timing characteristics and pinout can eliminate design issues and can create opportunities for applications that previously may not have existed. A major advantage is that the ASIC can adapt any I/O pin out to match the attached chips. This increases performance and greatly reduces the PCB design effort.

[0019] FIG. 2 illustrates the ASIC 102 being coupled to a chip 150 with different timing than the chip in FIG. 1. If the vendor of the external device that the ASIC 102 is attached to changes its timing specification, the new timing can be met by simply adjusting the I/O timing configuration provided by the FPGA function 104. Accordingly, choosing a new vendor and/or re-spin of the PCB is avoided.

[0020] In a preferred embodiment, the manufacturer of the ASIC 102 will know what applications and external devices that it will connect to. Testing will be done by the manufacturer of ASIC 102 to determine the correct I/O characteristics on a suit of different applications and various external devices that ASIC 102 is intended for. A set of different configurations will be available to the customer. The customer will choose an I/O configuration depending on how the ASIC 102 is used in the application. Only minimal timing analysis need to be completed to ensure a successful design. The FPGA function 104 controls the I/O configuration block 106. The pin layout of the ASIC 102 and chip 100 will be considered. The ASIC 102 pin layout will be remapped to line up with the chip 100 pin out. This will reduce the length of the PCB traces and greatly reduce the effort of PCB layout. It can also reduce the crosstalk between signals by having a straight path between the ASIC 102 and chip 100.

[0021] Once the configuration is set the system can be tuned to provide optimal performance. Two tuning techniques are described in detail hereinbelow.

[0022] Logic Analyzer Tuning

[0023] FIG. 3 illustrates the use of a logic analyzer to collect data and modify the configuration file of the FPGA

function. As is seen in FIG. 2, a logic analyzer 200 monitors the I/O signals 110 to ensure that the signals between the signals 110 are within its timing specifications. FIG. 3A illustrates two signals (signal a and signal b) before an adjustment. As is seen, signal a and signal b can have timing problems because they rise and fall in a corresponding fashion. The logic analyzer can modify the I/O configuration file in accordance with known programming techniques and therefore the timing performance can be optimized. In this embodiment signal b is delayed a shown in FIG. 3B to correct timing problems.

[0024] EMC Analyzer Tuning

[0025] FIG. 4 illustrates the use of an electromagnetic compatibility (EMC) analyzer 400 that can be used similarly to obtain information to be used to modify the I/O configuration to ensure that there is EMC compliance. The I/O timing characteristics can be changed by modifying the I/O configuration file in accordance with known programming techniques while the product is in an EMC chamber. This can save a vast amount of time not having to re-spin a PCB in order to meet EMC requirements. Accordingly, the I/O timing characteristics can be tuned to give the optimal performance to overcome process variations of ASICs and external devices.

[0026] Although the above-identified two tuning techniques are disclosed, numerous other tuning techniques could be utilized and they would be within the spirit and scope of the present invention.

[0027] Conclusion

[0028] A system in accordance with the present invention reduces the cost and time associated with the timing analysis activities during development. An FPGA cell function within the ASIC is utilized to control the I/O characteristics such as delay, termination and/or slew rate for the I/O. Different I/O configurations will be provided by the FPGA function depending on the environment the ASIC is used in. By providing an ASIC that is adaptable to different timing criteria through FPGA programming, the timing analysis performed by the user of the ASIC will be substantially reduced, resulting in a reduction of the development cycle.

[0029] Although the present invention has been described in accordance with the embodiments shown, one of ordinary skill in the art will readily recognize that there could be variations to the embodiments and those variations would be within the spirit and scope of the present invention. Accordingly, many modifications may be made by one of ordinary skill in the art without departing from the spirit and scope of the appended claims.

What is claimed is:

1. An application specific integrated circuit (ASIC) comprising:

a standard cell, the standard cell including a plurality of logic functions;

an input/output (I/O) configuration function coupled to at least a portion of the logic functions; and

a field programmable gate array (FPGA) function coupled to the I/O configuration function; wherein the FPGA function controls the I/O configuration function based upon a configuration information provided thereto.

2. The ASIC of claim 1 wherein the configuration information comprises a configuration file.

3. The ASIC of claim 1 wherein the I/O configuration function comprises:

adjustable delay logic for receiving a configuration file from the FPGA function; and

an I/O driver coupled to the adjustable delay logic for providing timing information.

4. The ASIC of claim 2 wherein the I/O driver is adapted to be coupled to the signals of an external chip and the configuration file provides the appropriate timing and to ensure pinouts of the external chip and the ASIC match.

5. The ASIC of claim 4 wherein the configuration file can be tuned to provide optimal performance of the ASIC.

6. The ASIC of claim 4 wherein the configuration file can be tuned utilizing a logic analyzer to monitor the signals for timing violations and to modify the configuration file in the FPGA function by conventional FPGA programming techniques.

7. The ASIC of claim 4 wherein the configuration information can be tuned utilizing an electromagnetic compatibility (EMC) analyzer to monitor magnetic compatibility and to modify the configuration file in the FPGA function by conventional FPGA programming techniques.

8. An ASIC (ASIC) comprising:

a standard cell, the standard cell including a plurality of logic functions;

a field programmable gate array (FPGA) function; and

an input/output (I/O) configuration function coupled to at least a portion of the logic functions and the FPGA functions, the I/O configuration function further comprising adjustable delay logic for receiving the configuration file from the FPGA function; and an I/O driver coupled to the adjustable delay logic for providing timing information, wherein the I/O driver is adapted to be coupled to the signals of the chip and the configuration file provides the appropriate timings and to ensure pinouts of the chip and the ASIC match, wherein the FPGA function controls the I/O configuration function based upon a configuration file provided thereto.

9. The ASIC of claim 8 wherein the configuration file can be tuned to provide optimal performance of the ASIC.

10. The ASIC of claim 8 wherein the configuration file can be tuned utilizing a logic analyzer to monitor the signals for timing violations and to modify the configuration file in the FPGA function by conventional FPGA programming techniques.

11. The ASIC of claim 8 wherein the configuration information can be tuned utilizing an electromagnetic compatibility (EMC) analyzer to monitor magnetic compatibility and to modify the configuration file in the FPGA function by conventional FPGA programming techniques.

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